TELEFUNKEN Semiconductors

TV East/West Correction Circuit for Square Tubes

Technology: Bipolar

Features

- Low dissipation
- Square generator for parabolic current specially designed for square C.R.T. correction
- External keystone adjustment (symmetry of the parabola)
- Input for dynamic field correction (beam current change)
- Static picture width adjustment
- Pulse-width modulator
- Final stage D-class with energy redelivery
- Parasitic parabola suppression, during flyback time of the vertical sawtooth

Case: 8 pin dual inline plastic

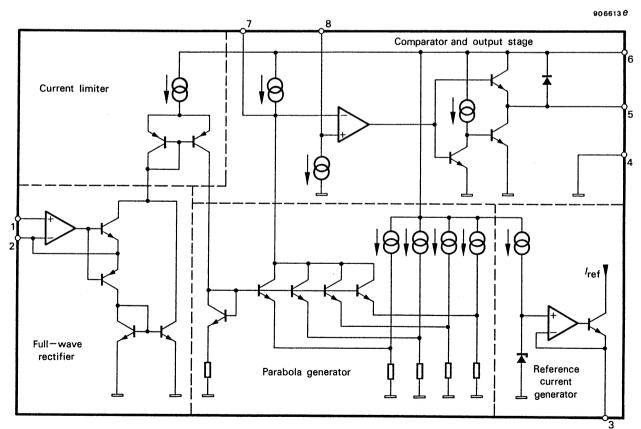


Figure 1. Block diagram

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Absolute Maximum Ratings

Parameters		Symbol	Value	Unit
Supply voltage	Pin 6	V_{S}	35	V
Supply current	Pin 6	I_{S}	500	mA
Power dissipation $T_{case} = 50$	o°C	P _{tot}	500	mW
Storage temperature range		T _{stg}	-25 to 150	°C
Junction temperature		Ti	−25 to 150	°C

Electrical Characteristics

 $V_S = 26 \text{ V}$, $T_{amb} = 25^{\circ}\text{C}$, Test circuits 1 to 5

Parameters	Test Conditions / Pins	Symbol	Min.	Тур.	Max.	Unit
Supply voltage	Pin 6	V_{S}	17	24	30	V
Supply current	Test circuit 1 Pin 6	I _S		4.5	7	mA
Reference voltage	Test circuit 1 Pin 3	V _{ref}	7.6	8.0	8.8	V
Voltage at Pin 7 *	Test circuit figure 2, Pin 7 $I_{fr} = 0 \; \mu A \\ I_{fr} = 30 \; \mu A$	V _{7A} V _{7C}	15.3	16.0 15.0	16.7	V
Parabola coefficient	$K_1 = \frac{V_{7A} - V_{7B}}{V_{7A} - V_{7C}}$			26		%
	$K_2 = \frac{V_{7A} - V_{7A}}{V_{7A} - V_{7A}}$	2		70		%
Difference, figure 2	$V_{DE7} = V_{7E} - V_{7F}$		-40	0	40	mV
Current source	Test circuit 3 Pin 8	I ₈		100		μΑ
Saturation voltage	$I_5 = 400 \text{ mA}, $ Pin 5 Test circuit 4	V _{satL}		1	2	V
	$I_5 = -100 \text{ mA}, \text{Pin 5}$ Test circuit 5	V _{satH}		0.8	1.5	V
Forward voltage	$I_5 = 400 \text{ mA},$ Pin 5 Test circuit 5	V_{F}		1.2	1.7	V

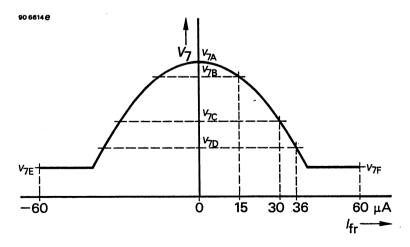


Figure 2. Parabola coefficients

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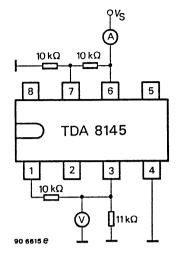


Figure 3. Test circuit 1

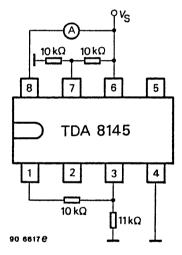


Figure 5. Test circuit 3

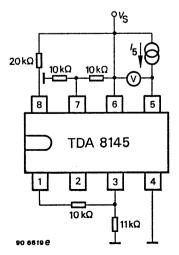


Figure 7. Test circuit 5

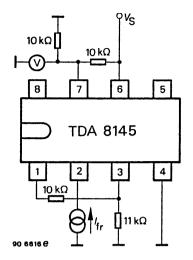


Figure 4. Test circuit 2

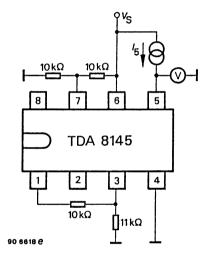


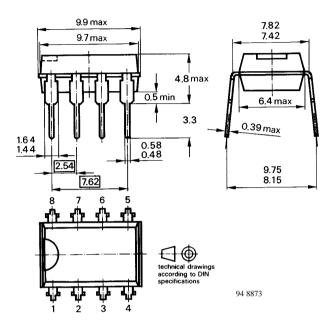
Figure 6. Test circuit 4

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Dimensions in mm

Package: DIP 8



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